

Search Notes

Application/Control No.

10/524,287

Examiner

Ren L. Yan

Applicant(s)/Patent under
Reexamination

ECKERT ET AL.

Art Unit

2854

SEARCHED

Class	Subclass	Date	Examiner
101	178 179	8/1/06	RY
	180		
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INTERFERENCE SEARCHED

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interference search print out		8/1/2006	RY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR